

Search Notes

Application/Control No.

10/760,353

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

TOYOMURA ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
363	131		
	132		
	146		
323	906		
307	66		
	150		
	151	5/15/2006	/JH/

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	5/15/2006	/JH/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner